

Special Issue

Advances and Application of Video and Digital Image Processing & Deep Learning

Message from the Guest Editor

The latest technological developments in video and digital image processing and deep learning will be shared through this Special Issue. We invite researchers and investigators to contribute their original research or review articles to this Special Issue.

Keywords

- artificial intelligence
- machine learning
- deep learning
- digital image processing
- digital video processing
- pattern recognition
- convolutional neural networks
- parallel computing

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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